

<b>Notice of References Cited</b>	Application/Control No. 10/582,386	Applicant(s)/Patent Under Reexamination YAMASHITA ET AL.	
	Examiner Ashraf Zahr	Art Unit 4135	Page 1 of 3

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,484,302 A	11-1984	Cason et al.	715/802
*	B	US-4,870,397 A	09-1989	Soto et al.	715/778
*	C	US-5,289,574 A	02-1994	Sawyer, Jon R.	715/759
*	D	US-5,386,505 A	01-1995	Beattie et al.	715/790
*	E	US-5,564,002 A	10-1996	Brown, Kurt R.	715/778
*	F	US-5,764,214 A	06-1998	Takano, Hajime	345/619
*	G	US-5,900,859 A	05-1999	Takishita et al.	345/629
*	H	US-5,959,639 A	09-1999	Wada, Tomohisa	345/542
*	I	US-6,133,898 A	10-2000	Ludolph et al.	715/790
*	J	US-2002/0037753 A1	03-2002	Shitahaku, Jun	455/566
*	K	US-6,573,915 B1	06-2003	Sivan et al.	715/781
*	L	US-6,593,945 B1	07-2003	Nason et al.	715/779
*	M	US-2003/0189597 A1	10-2003	Anderson et al.	345/778

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

<b>Notice of References Cited</b>	Application/Control No. 10/582,386		Applicant(s)/Patent Under Reexamination YAMASHITA ET AL.	
	Examiner Ashraf Zahr		Art Unit 4135	Page 2 of 3

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,630,943 B1	10-2003	Nason et al.	715/746
*	B	US-6,639,613 B1	10-2003	Nason et al.	715/778
*	C	US-6,686,936 B1	02-2004	Nason et al.	715/778
*	D	US-6,710,790 B1	03-2004	Fagioli, James O.	715/802
*	E	US-6,727,918 B1	04-2004	Nason, D. David	715/791
*	F	US-6,828,991 B2	12-2004	Nason et al.	715/778
*	G	US-6,831,666 B1	12-2004	Kreis, Alexander T.	715/781
*	H	US-6,892,359 B1	05-2005	Nason et al.	715/788
*	I	US-6,917,362 B2	07-2005	Pinedo et al.	345/530
*	J	US-6,966,036 B2	11-2005	Nason et al.	715/778
*	K	US-7,010,755 B2	03-2006	Anderson et al.	715/778
*	L	US-7,043,697 B1	05-2006	Jensen et al.	715/788
*	M	US-7,103,850 B1	09-2006	Engstrom et al.	715/778

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

<b>Notice of References Cited</b>	Application/Control No. 10/582,386	Applicant(s)/Patent Under Reexamination YAMASHITA ET AL.	
	Examiner Ashraf Zahr	Art Unit 4135	Page 3 of 3

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-7,190,883 B2	03-2007	Yeo, Boon-Lock	386/109
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.